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HI5805

12-Bit, 5MSPS A/D Converter

FN3984
Rev 7.00
March 31, 2005

The HI5805 is a monolithic, 12-bit, Analog-to-Digital Converter fabricated in Intersil's HBC10 BiCMOS process. It is designed for high speed, high resolution applications where wide bandwidth and low power consumption are essential.

The HI5805 is designed in a fully differential pipelined architecture with a front end differential-in-differential-out sample-and-hold (S/H). The HI5805 has excellent dynamic performance while consuming 300mW power at 5MSPS.

The 100MHz full power input bandwidth is ideal for communication systems and document scanner applications. Data output latches are provided which present valid data to the output bus with a latency of 3 clock cycles. The digital outputs have a separate supply pin which can be powered from a 3.0V to 5.0V supply.

Ordering Information

PART NUMBER	SAMPLE RATE	TEMP. RANGE (^{o}C)	PACKAGE	PKG. DWG. #
HI5805BIB	5MSPS	-40 to 85	28 Ld SOIC (W)	M28.3
HI5805BIBZ (See Note)	5MSPS	-40 to 85	28 Ld SOIC (W) (Pb-free)	M28.3
HI5805EVAL1		25	Evaluation Board	

NOTE: Intersil Pb-free products employ special Pb-free material sets; molding compounds/die attach materials and 100% matte tin plate termination finish, which are RoHS compliant and compatible with both SnPb and Pb-free soldering operations. Intersil Pb-free products are MSL classified at Pb-free peak reflow temperatures that meet or exceed the Pb-free requirements of IPC/JEDEC J STD-020.

Features

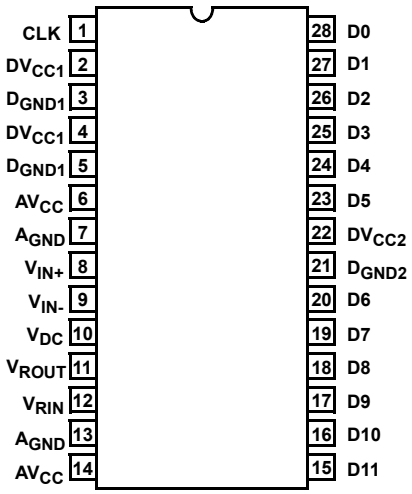
- Sampling Rate 5MSPS
- Low Power
- Internal Sample and Hold
- Fully Differential Architecture
- Full Power Input Bandwidth 100MHz
- Low Distortion
- Internal Voltage Reference
- TTL/CMOS Compatible Digital I/O
- Digital Outputs . . . . . 5V to 3.0V
- Pb-Free Available (RoHS Compliant)

Applications

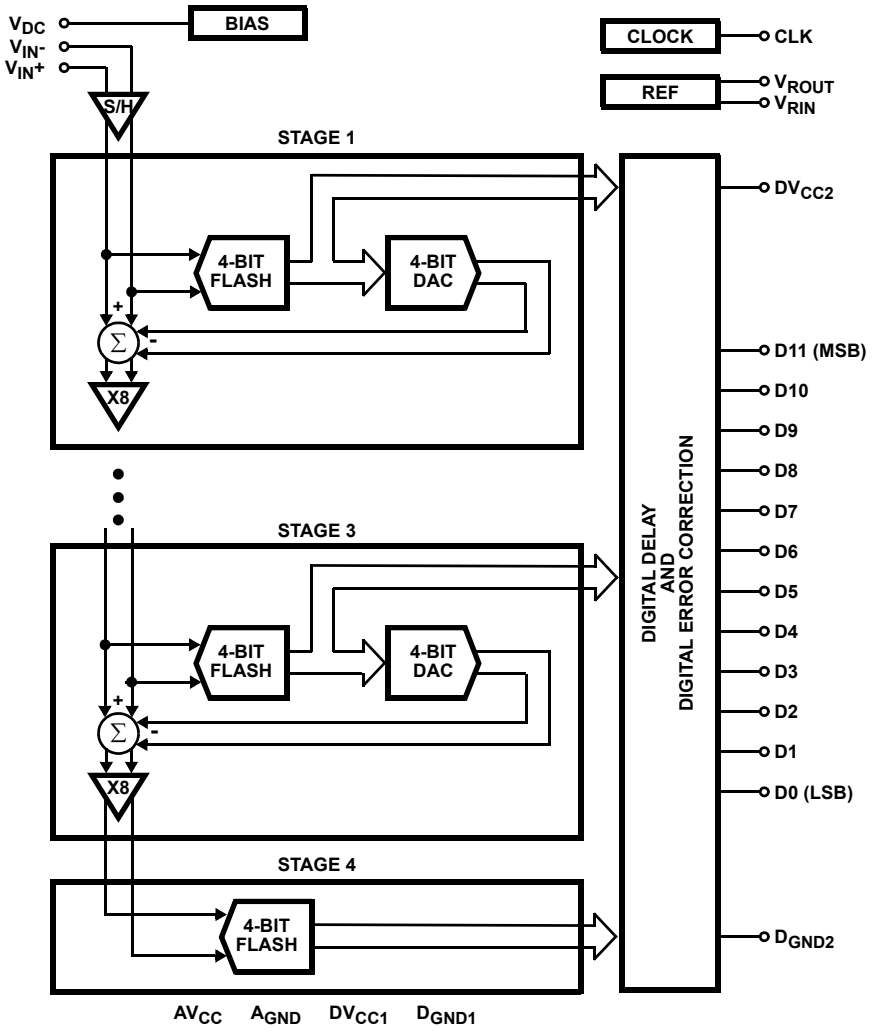
- Digital Communication Systems
- Undersampling Digital IF
- Document Scanners
- Additional Reference Documents
  - AN9214 Using Intersil High Speed A/D Converters
  - AN9707 Using the HI5805EVAL1 Evaluation Board

Pinout

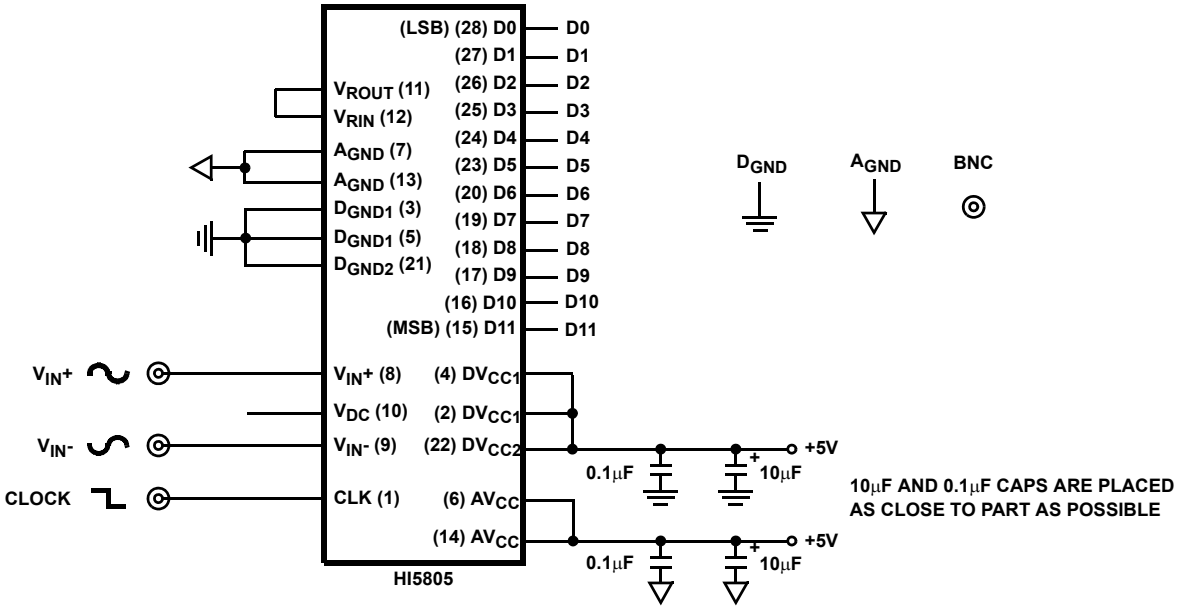
HI5805
(SOIC)
TOP VIEW



Functional Block Diagram



Typical Application Schematic



Absolute Maximum Ratings

Supply Voltage, AV_{CC} or DV_{CC} to A_{GND} or D_{GND} . . . . . +6.0V
D_{GND} to A_{GND} 0.3V
Digital I/O Pins . . . . . D_{GND} to DV_{CC}
Analog I/O Pins . . . . . A_{GND} to AV_{CC}

Operating Conditions

Temperature Range, HI5805BIB . . . . . -40°C to 85°C

Thermal Information

Thermal Resistance (Typical, Note 1)	θ_{JA} (°C/W)
SOIC Package	70

Maximum Junction Temperature . . . . . 150°C
Maximum Storage Temperature Range . . . . . -65°C to 150°C
Maximum Lead Temperature (Soldering, 10s) . . . . . 300°C
(SOIC - Lead Tips Only)

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

1. θ_{JA} is measured with the component mounted on an evaluation PC board in free air.

Electrical Specifications

$AV_{CC} = DV_{CC1} = DV_{CC2} = DV_{CC3} = +5.0V$, $f_S = 5MSPS$ at 50% Duty Cycle, $V_{RIN} = 3.5V$, $C_L = 10pF$, $T_A = -40°C$ to 85°C, Differential Analog Input, Typical Values are Test Results at 25°C, Unless Otherwise Specified

PARAMETER	TEST CONDITION	HI5805BIB (-40°C TO 85°C)			UNITS
		MIN	TYP	MAX	
ACCURACY					
Resolution		12	-	-	Bits
Integral Linearity Error, INL	f_{IN} = DC	-	±1	±2	LSB
Differential Linearity Error, DNL (Guaranteed No Missing Codes)	f_{IN} = DC	-	±0.5	±1	LSB
Offset Error, V_{OS}	f_{IN} = DC	-	19	-	LSB
Full Scale Error, FSE	f_{IN} = DC	-	32	-	LSB
DYNAMIC CHARACTERISTICS					
Minimum Conversion Rate	No Missing Codes	-	0.5	-	MSPS
Maximum Conversion Rate	No Missing Codes	5	-	-	MSPS
Effective Number of Bits, ENOB	f_{IN} = 1MHz	10.0	11	-	Bits
Signal to Noise and Distortion Ratio, SINAD $= \frac{\text{RMS Signal}}{\text{RMS Noise + Distortion}}$	f_{IN} = 1MHz	-	68	-	dB
Signal to Noise Ratio, SNR $= \frac{\text{RMS Signal}}{\text{RMS Noise}}$	f_{IN} = 1MHz	-	68	-	dB
Total Harmonic Distortion, THD	f_{IN} = 1MHz	-	-80	-	dBc
2nd Harmonic Distortion	f_{IN} = 1MHz	-	-86		dBc
3rd Harmonic Distortion	f_{IN} = 1MHz	-	-83	-	dBc
Spurious Free Dynamic Range, SFDR	f_{IN} = 1MHz	-	83	-	dBc
Intermodulation Distortion, IMD	f_1 = 1MHz, f_2 = 1.02MHz	-	-68	-	dBc
Transient Response		-	1	-	Cycle
Over-Voltage Recovery	0.2V Overdrive	-	2	-	Cycle
ANALOG INPUT					
Maximum Peak-to-Peak Differential Analog Input Range ($V_{IN}+ - V_{IN}-$)		-	±2.0	-	V
Maximum Peak-to-Peak Single-Ended Analog Input Range		-	4.0	-	V
Analog Input Resistance, R_{IN}	(Notes 2, 3)	1	-	-	MΩ
Analog Input Capacitance, C_{IN}		-	10	-	pF
Analog Input Bias Current, $I_{B}+$ or $I_{B}-$	(Note 3)	-10	-	+10	µA
Differential Analog Input Bias Current $I_{B\ DIFF} = (I_{B}+ - I_{B}-)$		-	±0.5	-	µA
Full Power Input Bandwidth, FPBW		-	100	-	MHz

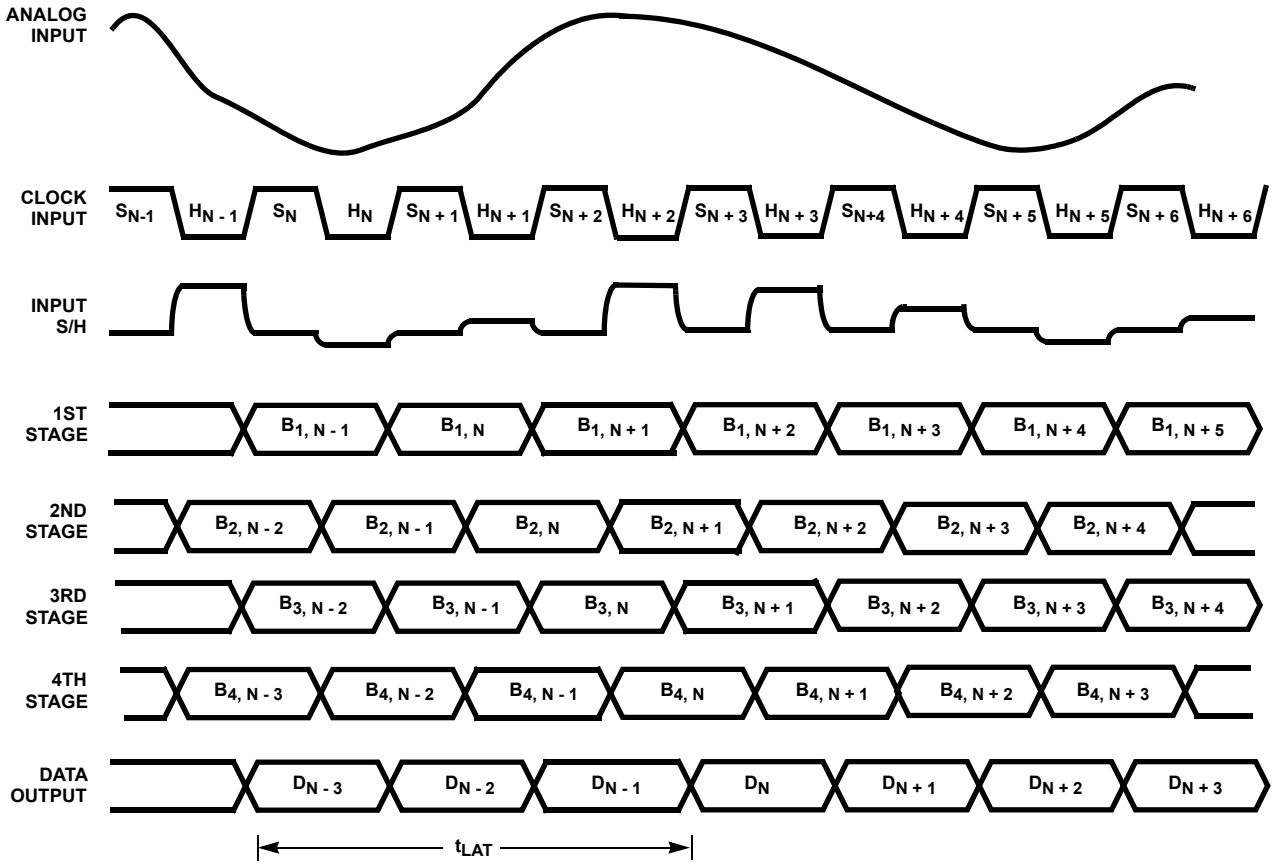
Electrical Specifications $AV_{CC} = DV_{CC1} = DV_{CC2} = DV_{CC3} = +5.0V$, $f_S = 5MSPS$ at 50% Duty Cycle, $V_{RIN} = 3.5V$, $C_L = 10pF$, $T_A = -40^oC$ to 85^oC, Differential Analog Input, Typical Values are Test Results at 25^oC, Unless Otherwise Specified **(Continued)**

PARAMETER	TEST CONDITION	HI5805BIB (-40°C TO 85°C)			UNITS
		MIN	TYP	MAX	
Analog Input Common Mode Voltage Range ($V_{IN}+ + V_{IN}-$)/2	Differential Mode (Note 2)	1	2.3	4	V
INTERNAL VOLTAGE REFERENCE					
Reference Output Voltage, V_{ROUT} (Loaded)		-	3.5	-	V
Reference Output Current		-	-	1	mA
Reference Temperature Coefficient		-	200	-	ppm/°C
REFERENCE VOLTAGE INPUT					
Reference Voltage Input, V_{RIN}		-	3.5	-	V
Total Reference Resistance, R_L		-	7.8	-	kΩ
Reference Current		-	450	-	µA
DC BIAS VOLTAGE					
DC Bias Voltage Output, V_{DC}		-	2.3	-	V
Max Output Current (Not To Exceed)		-	-	1	mA
DIGITAL INPUTS (CLK)					
Input Logic High Voltage, V_{IH}		2.0	-	-	V
Input Logic Low Voltage, V_{IL}		-	-	0.8	V
Input Logic High Current, I_{IH}	$V_{CLK} = 5V$	-	-	10.0	µA
Input Logic Low Current, I_{IL}	$V_{CLK} = 0V$	-	-	10.0	µA
Input Capacitance, C_{IN}		-	7	-	pF
DIGITAL OUTPUTS (D0-D11)					
Output Logic Sink Current, I_{OL}	$V_O = 0.4V$ (Note 2)	1.6	-	-	mA
	$DV_{CC3} = 3.0V$, $V_O = 0.4V$	-	1.6	-	mA
Output Logic Source Current, I_{OH}	$V_O = 2.4V$ (Note 2)	-0.2	-	-	mA
	$DV_{CC3} = 3.0V$, $V_O = 2.4V$	-	-0.2	-	mA
Output Capacitance, C_{OUT}		-	5	-	pF
TIMING CHARACTERISTICS					
Aperture Delay, t_{AP}		-	5	-	ns
Aperture Jitter, t_{AJ}		-	5	-	ps (RMS)
Data Output Delay, t_{OD}		-	8	-	ns
Data Output Hold, t_H		-	8	-	ns
Data Latency, t_{LAT}	For a Valid Sample (Note 2)	-	-	3	Cycles
Clock Pulse Width (Low)	5MSPS Clock	90	100	110	ns
Clock Pulse Width (High)	5MSPS Clock	90	100	110	ns
POWER SUPPLY CHARACTERISTICS					
Total Supply Current, I_{CC}	$V_{IN}+ - V_{IN}- = 2V$	-	60	70	mA
Analog Supply Current, AI_{CC}	$V_{IN}+ - V_{IN}- = 2V$	-	46	-	mA
Digital Supply Current, DI_{CC1}	$V_{IN}+ - V_{IN}- = 2V$	-	13	-	mA
Output Supply Current, DI_{CC2}	$V_{IN}+ - V_{IN}- = 2V$	-	1	-	mA
Power Dissipation	$V_{IN}+ - V_{IN}- = 2V$	-	300	350	mW
Offset Error PSRR, ΔV_{OS}	AV_{CC} or $DV_{CC} = 5V \pm 5\%$	-	2	-	LSB
Gain Error PSRR, ΔFSE	AV_{CC} or $DV_{CC} = 5V \pm 5\%$	-	30	-	LSB

NOTES:

2. Parameter guaranteed by design or characterization and not production tested.
3. With the clock off (clock low, hold mode).

Timing Waveforms



NOTES:

4. S_N: N-th sampling period.
5. H_N: N-th holding period.
6. $B_{M,N}$: M-th stage digital output corresponding to N-th sampled input.
7. D_N: Final data output corresponding to N-th sampled input.

FIGURE 1. INTERNAL CIRCUIT TIMING

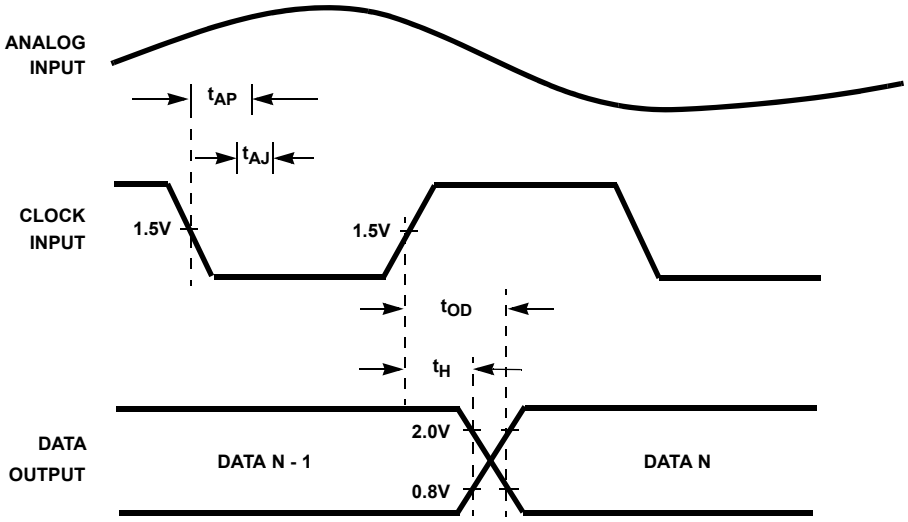


FIGURE 2. INPUT-TO-OUTPUT TIMING

Typical Performance Curves

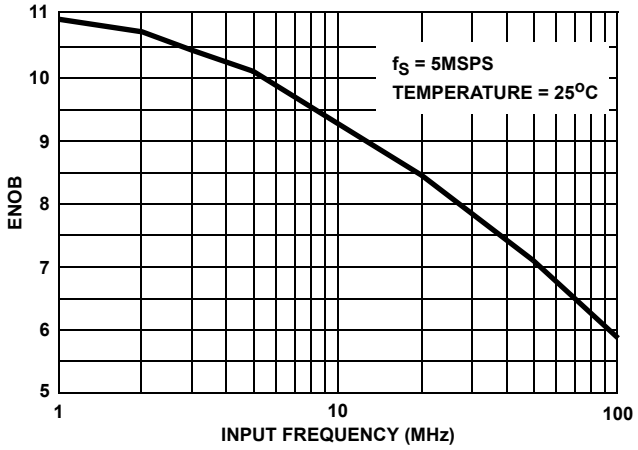


FIGURE 3. EFFECTIVE NUMBER OF BITS (ENOB) vs INPUT FREQUENCY

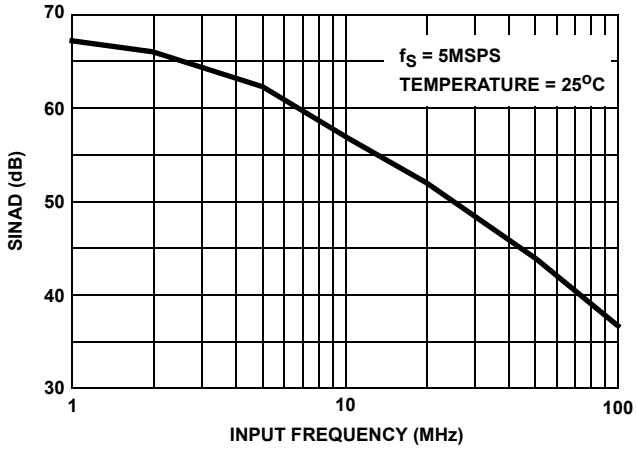


FIGURE 4. SIGNAL TO NOISE AND DISTORTION (SINAD) vs INPUT FREQUENCY

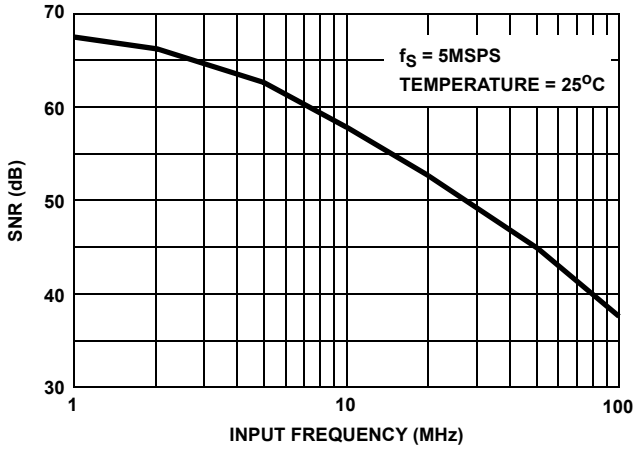


FIGURE 5. SIGNAL TO NOISE RATIO (SNR) vs INPUT FREQUENCY

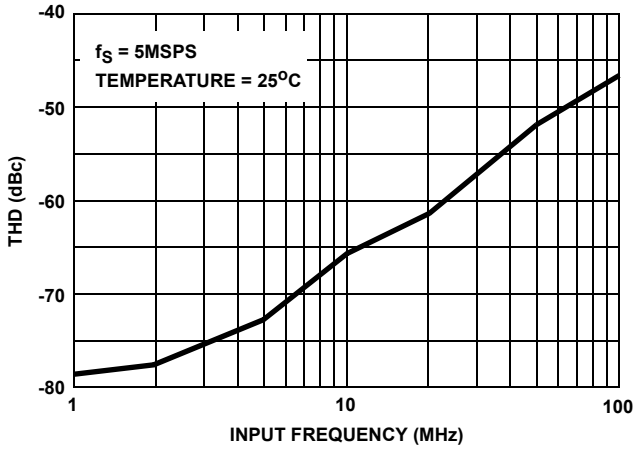


FIGURE 6. TOTAL HARMONIC DISTORTION (THD) vs INPUT FREQUENCY

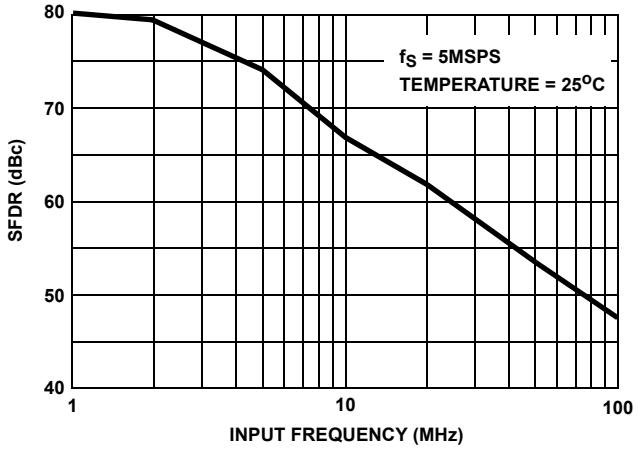


FIGURE 7. SPURIOUS FREE DYNAMIC RANGE (SFDR) vs INPUT FREQUENCY

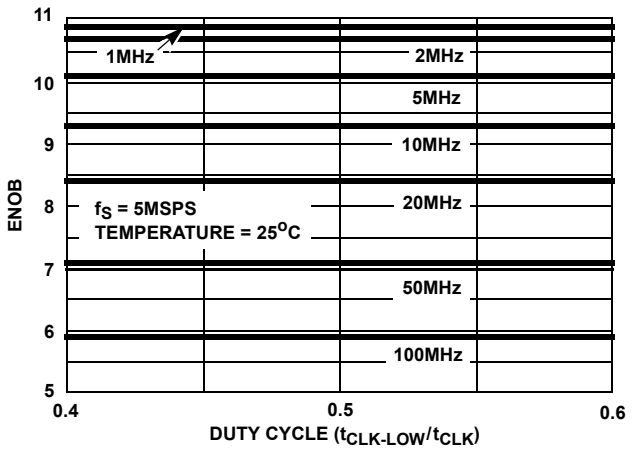


FIGURE 8. EFFECTIVE NUMBER OF BITS (ENOB) vs CLOCK DUTY CYCLE AND INPUT FREQUENCY

Typical Performance Curves (Continued)

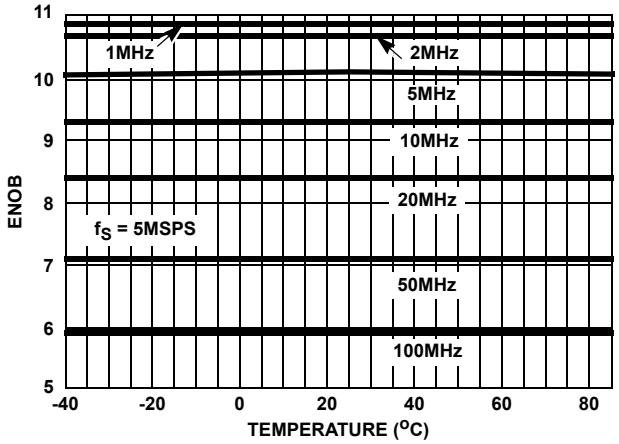


FIGURE 9. EFFECTIVE NUMBER OF BITS (ENOB) vs TEMPERATURE AND INPUT FREQUENCY

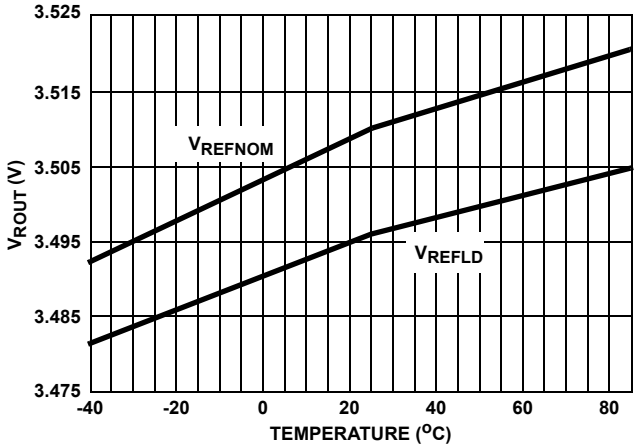


FIGURE 10. INTERNAL VOLTAGE REFERENCE OUTPUT (VROUT) vs TEMPERATURE AND LOAD

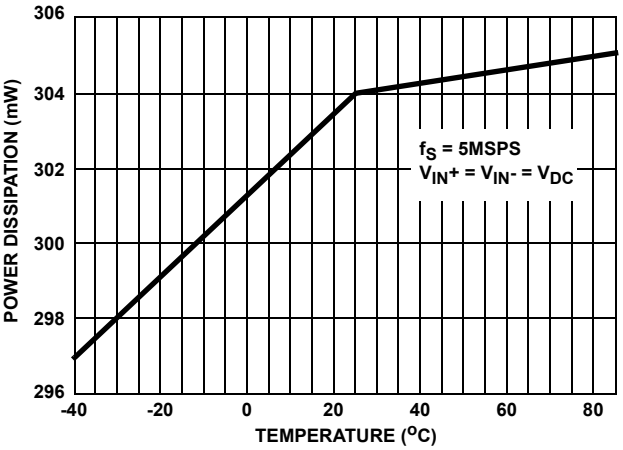


FIGURE 11. POWER DISSIPATION vs TEMPERATURE

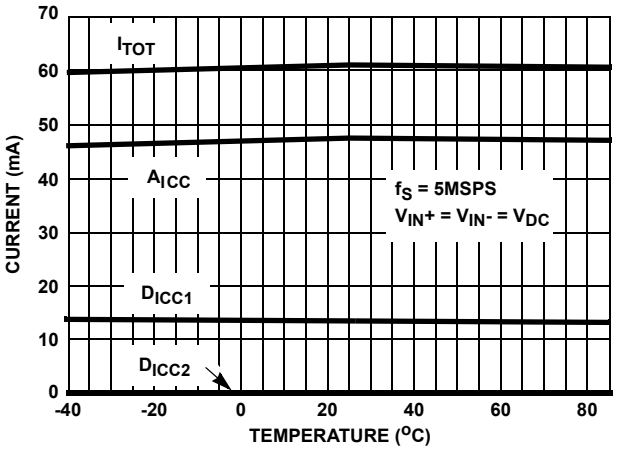


FIGURE 12. POWER SUPPLY CURRENT vs TEMPERATURE

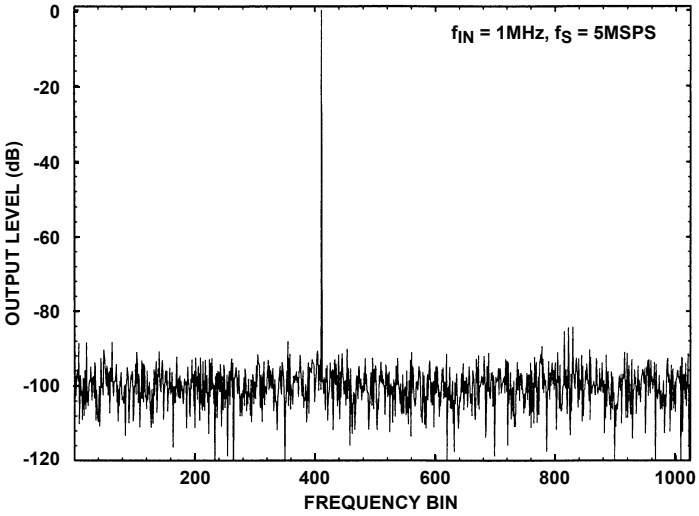


FIGURE 13. 2048 POINT FFT SPECTRAL PLOT

Pin Descriptions

PIN NO.	NAME	DESCRIPTION
1	CLK	Input Clock.
2	DV_{CC1}	Digital Supply (5.0V).
3	D_{GND1}	Digital Ground.
4	DV_{CC1}	Digital Supply (5.0V).
5	D_{GND1}	Digital Ground
6	AV_{CC}	Analog Supply (5.0V).
7	A_{GND}	Analog Ground.
8	$V_{IN}+$	Positive Analog Input.
9	$V_{IN}-$	Negative Analog Input.
10	V_{DC}	DC Bias Voltage Output.
11	V_{ROUT}	Reference Voltage Output.
12	V_{RIN}	Reference Voltage Input.
13	A_{GND}	Analog Ground.
14	AV_{CC}	Analog Supply (5.0V).
15	D11	Data Bit 11 Output (MSB).
16	D10	Data Bit 10 Output.
17	D9	Data Bit 9 Output.
18	D8	Data Bit 8 Output.
19	D7	Data Bit 7 Output.
20	D6	Data Bit 6 Output.
21	D_{GND2}	Digital Output Ground.
22	DV_{CC2}	Digital Output Supply (3.0V to 5.0V).
23	D5	Data Bit 5 Output.
24	D4	Data Bit 4 Output.
25	D3	Data Bit 3 Output.
26	D2	Data Bit 2 Output.
27	D1	Data Bit 1 Output.
28	D0	Data Bit 0 Output (LSB).

Detailed Description

Theory of Operation

The HI5805 is a 12-bit, fully-differential, sampling pipeline A/D converter with digital error correction. Figure 14 depicts the circuit for the front end differential-in-differential-out sample-and-hold (S/H). The switches are controlled by an internal clock which is a non-overlapping two phase signal, f_1 and f_2, derived from the master clock. During the sampling phase, f_1, the input signal is applied to the sampling capacitors, C_S. At the same time the holding capacitors, C_H, are discharged to analog ground. At the falling edge of f_1 the input signal is sampled on the bottom plates of the sampling capacitors. In the next clock phase, f_2, the two bottom plates of the sampling capacitors are connected together and the holding capacitors are switched to the op-amp output nodes. The charge then redistributes between C_S and C_H completing one sample-and-hold cycle. The output is a fully-differential, sampled-data representation of the analog input. The circuit not only performs the sample-and-hold function but will also convert a single-ended input to a fully-differential output for the converter core. During the sampling phase, the V_{IN} pins see only the on-resistance of a switch and C_S. The relatively small values of these components result in a typical full power input bandwidth of 100MHz for the converter.

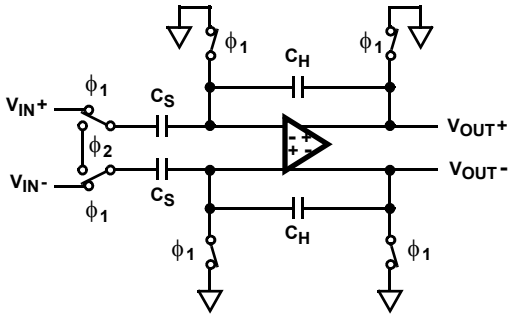


FIGURE 14. ANALOG INPUT SAMPLE-AND-HOLD

As illustrated in the functional block diagram and the timing diagram in Figure 1, three identical pipeline subconverter stages, each containing a four-bit flash converter, a four-bit digital-to-analog converter and an amplifier with a voltage gain of 8, follow the S/H circuit with the fourth stage being only a 4-bit flash converter. Each converter stage in the pipeline will be sampling in one phase and amplifying in the other clock phase. Each individual sub-converter clock signal is offset by 180 degrees from the previous stage clock signal, with the result that alternate stages in the pipeline will perform the same operation.

The 4-bit digital output of each stage is fed to a digital delay line controlled by the internal clock. The purpose of the delay line is to align the digital output data to the corresponding sampled analog input signal. This delayed data is fed to the digital error correction circuit which corrects the error in the output data with the information contained in the redundant bits to form the final 12-bit output for the converter.

Because of the pipeline nature of this converter, the data on the bus is output at the 3rd cycle of the clock after the analog sample is taken. This delay is specified as the data latency. After the data latency time, the data representing each succeeding sample is output at the following clock pulse. The output data is synchronized to the external clock by a latch. The digital outputs are in offset binary format (See Table 1).

Internal Reference Generator, V_{ROUT} and V_{RIN}

The HI5805 has an internal reference generator, therefore, no external reference voltage is required. V_{ROUT} must be connected to V_{RIN} when using the internal reference voltage.

The HI5805 can be used with an external reference. The converter requires only one external reference voltage connected to the V_{RIN} pin with V_{ROUT} left open.

The HI5805 is tested with V_{RIN} equal to 3.5V. Internal to the converter, two reference voltages of 1.3V and 3.3V are generated for a fully differential input signal range of ±2V.

In order to minimize overall converter noise, it is recommended that adequate high frequency decoupling be provided at the reference voltage input pin, V_{RIN}.

TABLE 1.

CODE CENTER DESCRIPTION	DIFFERENTIAL INPUT VOLTAGE† (USING INTERNAL REFERENCE)	OFFSET BINARY OUTPUT CODE											
		MSB											LSB
		D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
+Full Scale (+FS) - $^1/_4$ LSB	+1.99976V	1	1	1	1	1	1	1	1	1	1	1	1
+FS - $1^1/_4$ LSB	1.99878V	1	1	1	1	1	1	1	1	1	1	1	0
+ $^3/_4$ LSB	732.4µV	1	0	0	0	0	0	0	0	0	0	0	0
- $^1/_4$ LSB	-244.1µV	0	1	1	1	1	1	1	1	1	1	1	1
-FS + $1^3/_4$ LSB	-1.99829V	0	0	0	0	0	0	0	0	0	0	0	1
-Full Scale (-FS) + $^3/_4$ LSB	-1.99927V	0	0	0	0	0	0	0	0	0	0	0	0

† The voltages listed above represent the ideal center of each offset binary output code shown.

Analog Input, Differential Connection

The analog input to the HI5805 can be configured in various ways depending on the signal source and the required level of performance. A fully differential connection (Figure 15) will give the best performance for the converter.

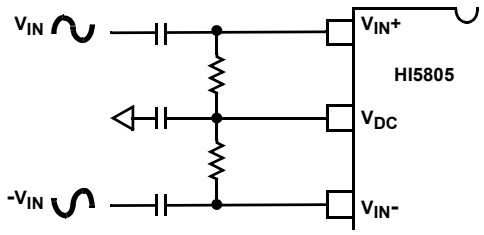


FIGURE 15. AC COUPLED DIFFERENTIAL INPUT

Since the HI5805 is powered off a single +5V supply, the analog input must be biased so it lies within the analog input common mode voltage range of 1.0V to 4.0V. The performance of the ADC does not change significantly with the value of the analog input common mode voltage.

A 2.3V DC bias voltage source, V_{DC}, half way between the top and bottom internal reference voltages, is made available to the user to help simplify circuit design when using a differential input. This low output impedance voltage source is not designed to be a reference but makes an excellent bias source and stays within the analog input common mode voltage range over temperature.

The difference between the converter's two internal voltage references is 2V. For the AC coupled differential input, (Figure 15), if V_{IN} is a $2V_{P-P}$ sinewave with $-V_{IN}$ being 180 degrees out of phase with V_{IN}, then $V_{IN}+$ is a $2V_{P-P}$ sinewave riding on a DC bias voltage equal to V_{DC} and $V_{IN}-$ is a $2V_{P-P}$ sinewave riding on a DC bias voltage equal to V_{DC}. Consequently, the converter will be at positive full scale, all 1s digital data output code, when the $V_{IN}+$ input is at V_{DC} +1V and the $V_{IN}-$ input is at V_{DC} -1V ($V_{IN}+ - V_{IN}- =$ 2V). Conversely, the ADC will be at negative full scale, all 0s digital data output code, when the $V_{IN}+$ input is equal to V_{DC}- 1V and $V_{IN}-$ is at $V_{DC}+1V$ ($V_{IN}+ - V_{IN}- = -2V$). From this, the converter is seen to have a peak-to-peak differential analog input voltage range of ±2V.

The analog input can be DC coupled (Figure 16) as long as the inputs are within the analog input common mode voltage range ($1.0V \leq VDC \leq 4.0V$).

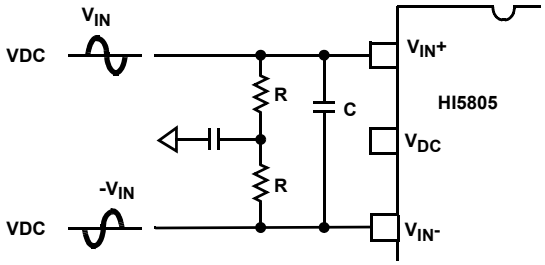


FIGURE 16. DC COUPLED DIFFERENTIAL INPUT

The resistors, R, in Figure 16 are not absolutely necessary but may be used as load setting resistors. A capacitor, C, connected from $V_{IN}+$ to $V_{IN}-$ will help filter any high frequency noise on the inputs, also improving performance. Values around 20pF are sufficient and can be used on AC coupled inputs as well. Note, however, that the value of capacitor C chosen must take into account the highest frequency component of the analog input signal.

Analog Input, Single-Ended Connection

The configuration shown in Figure 17 may be used with a single ended AC coupled input. Sufficient headroom must be provided such that the input voltage never goes above +5V or below A_{GND}.

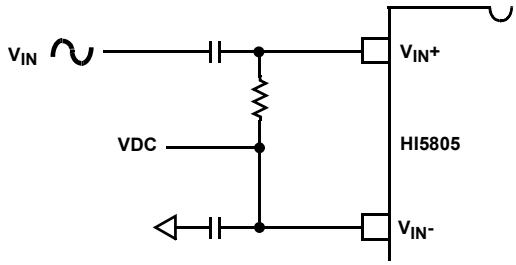


FIGURE 17. AC COUPLED SINGLE ENDED INPUT

Again, the difference between the two internal voltage references is 2V. If V_{IN} is a $4V_{P-P}$ sinewave, then $V_{IN}+$ is a $4V_{P-P}$ sinewave riding on a positive voltage equal to VDC. The converter will be at positive full scale when $V_{IN}+$ is at VDC + 2V ($V_{IN}+ - V_{IN}- = 2V$) and will be at negative full scale when $V_{IN}+$ is equal to VDC - 2V ($V_{IN}+ - V_{IN}- = -2V$). In this case, V_{DC} could range between 2V and 3V without a significant change in ADC performance. The simplest way to produce VDC is to use the V_{DC} bias voltage output of the HI5805.

The single ended analog input can be DC coupled (Figure 18) as long as the input is within the analog input common mode voltage range.

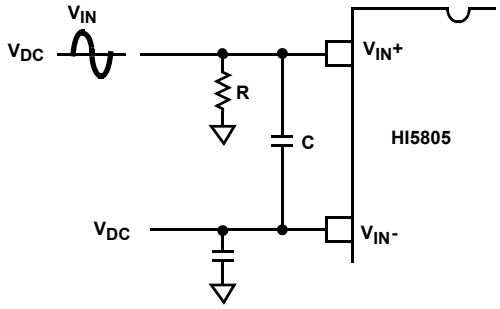


FIGURE 18. DC COUPLED SINGLE ENDED INPUT

The resistor, R, in Figure 18 is not absolutely necessary but may be used as a load setting resistor. A capacitor, C, connected from $V_{IN}+$ to $V_{IN}-$ will help filter any high frequency noise on the inputs, also improving performance. Values around 20pF are sufficient and can be used on AC coupled inputs as well. Note, however, that the value of capacitor C chosen must take into account the highest frequency component of the analog input signal.

A single ended source will give better overall system performance if it is first converted to differential before driving the HI5805.

Digital I/O and Clock Requirements

The HI5805 provides a standard high-speed interface to external TTL/CMOS logic families. The digital CMOS clock input has TTL level thresholds. The low input bias current allows the HI5805 to be driven by CMOS logic.

The digital CMOS outputs have a separate digital supply. This allows the digital outputs to operate from a 3.0V to 5.0V supply. When driving CMOS logic, the digital outputs will swing to the rails. When driving standard TTL loads, the digital outputs will meet standard TTL level requirements even with a 3.0V supply.

In order to ensure rated performance of the HI5805, the duty cycle of the clock should be held at 50% ±5%. It must also have low jitter and operate at standard TTL levels.

Performance of the HI5805 will only be guaranteed at conversion rates above 0.5MSPS. This ensures proper performance of the internal dynamic circuits.

Supply and Ground Considerations

The HI5805 has separate analog and digital supply and ground pins to keep digital noise out of the analog signal path. The part should be mounted on a board that provides separate low impedance connections for the analog and digital supplies and grounds. For best performance, the supplies to the HI5805 should be driven by clean, linear regulated supplies. The board should also have good high frequency decoupling capacitors mounted as close as possible to the converter. If the part is powered off a single supply then the analog supply and ground pins should be isolated by ferrite beads from the digital supply and ground pins.

Refer to the Application Note AN9214, “Using Intersil High Speed A/D Converters” for additional considerations when using high speed converters.

Static Performance Definitions

Offset Error (V_{OS})

The midscale code transition should occur at a level $^1/_4$ LSB above half scale. Offset is defined as the deviation of the actual code transition from this point.

Full-Scale Error (FSE)

The last code transition should occur for an analog input that is $^3/_4$ LSB below positive full scale with the offset error removed. Full-scale error is defined as the deviation of the actual code transition from this point.

Differential Linearity Error (DNL)

DNL is the worst case deviation of a code width from the ideal value of 1 LSB.

Integral Linearity Error (INL)

INL is the worst case deviation of a code center from a best fit straight line calculated from the measured data.

Power Supply Rejection Ratio (PSRR)

Each of the power supplies are moved plus and minus 5% and the shift in the offset and gain error (in LSBs) is noted.

Dynamic Performance Definitions

Fast Fourier Transform (FFT) techniques are used to evaluate the dynamic performance of the HI5805. A low distortion sine wave is applied to the input, it is coherently sampled, and the output is stored in RAM. The data is then transformed into the frequency domain with an FFT and analyzed to evaluate the dynamic performance of the A/D. The sine wave input to the part is -0.5dB down from full scale for all these tests. SNR and SINAD are quoted in dB. The distortion numbers are quoted in dBc (decibels with respect to carrier) and **DO NOT** include any correction factors for normalizing to full scale.

Signal-to-Noise Ratio (SNR)

SNR is the measured RMS signal to RMS noise at a specified input and sampling frequency. The noise is the RMS sum of all of the spectral components except the fundamental and the first five harmonics.

Signal-to-Noise + Distortion Ratio (SINAD)

SINAD is the measured RMS signal to RMS sum of all other spectral components below the Nyquist frequency, $f_S/2$, excluding DC.

Effective Number Of Bits (ENOB)

The effective number of bits (ENOB) is calculated from the SINAD data by:

$$ENOB = (SINAD + V_{CORR} - 1.76)/6.02,$$

where: $V_{CORR} = 0.5dB$.

V_{CORR} adjusts the ENOB for the amount the input is below fullscale.

Total Harmonic Distortion (THD)

THD is the ratio of the RMS sum of the first 5 harmonic components to the RMS value of the fundamental input signal.

2nd and 3rd Harmonic Distortion

This is the ratio of the RMS value of the applicable harmonic component to the RMS value of the fundamental input signal.

Spurious Free Dynamic Range (SFDR)

SFDR is the ratio of the fundamental RMS amplitude to the RMS amplitude of the next largest spur or spectral component in the spectrum below $f_S/2$.

Intermodulation Distortion (IMD)

Nonlinearities in the signal path will tend to generate intermodulation products when two tones, f_1 and f_2, are present at the inputs. The ratio of the measured signal to the distortion terms is calculated. The terms included in the calculation are $(f_1 + f_2)$, $(f_1 - f_2)$, $(2f_1)$, $(2f_2)$, $(2f_1 + f_2)$, $(2f_1 - f_2)$, $(f_1 + 2f_2)$, $(f_1 - 2f_2)$. The ADC is tested with each tone 6dB below full scale.

Transient Response

Transient response is measured by providing a full-scale transition to the analog input of the ADC and measuring the number of cycles it takes for the output code to settle within 12-bit accuracy.

Over-Voltage Recovery

Over-voltage Recovery is measured by providing a full-scale transition to the analog input of the ADC which overdrives the input by 200mV, and measuring the number of cycles it takes for the output code to settle within 12-bit accuracy.

Full Power Input Bandwidth (FPBW)

Full power input bandwidth is the analog input frequency at which the amplitude of the digitally reconstructed output has decreased 3dB below the amplitude of the input sinewave. The input sinewave has an amplitude which swings from $-f_S$ to $+f_S$. The bandwidth given is measured at the specified sampling frequency.

Timing Definitions

Refer to Figure 1, Internal Circuit Timing, and Figure 2, Input-To-Output Timing, for these definitions.

Aperture Delay (t_{AP})

Aperture delay is the time delay between the external sample command (the falling edge of the clock) and the time at which the signal is actually sampled. This delay is due to internal clock path propagation delays.

Aperture Jitter (t_{AJ})

Aperture Jitter is the RMS variation in the aperture delay due to variation of internal clock path delays.

Data Hold Time (t_H)

Data hold time is the time to where the previous data (N - 1) is no longer valid.

Data Output Delay Time (t_{OD})

Data output delay time is the time to where the new data (N) is valid.

Data Latency (t_{LAT})

After the analog sample is taken, the digital data is output on the bus at the third cycle of the clock. This is due to the pipeline nature of the converter where the data has to ripple through the stages. This delay is specified as the data latency. After the data latency time, the data representing each succeeding sample is output at the following clock pulse. The digital data lags the analog input sample by 3 clock cycles.